

## FDD6685

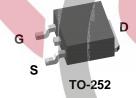
# 30V P-Channel PowerTrench<sup>o</sup> MOSFET

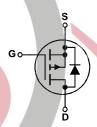
## **General Description**

This P-Channel MOSFET is a rugged gate version of Fairchild Semiconductor's advanced PowerTrench process. It has been optimized for power management applications requiring a wide range of gave drive voltage ratings (4.5V – 25V).

### **Features**

- -40 A, -30 V.  $R_{DS(ON)}=20~m\Omega$  @  $V_{GS}=-10~V$   $R_{DS(ON)}=30~m\Omega$  @  $V_{GS}=-4.5~V$
- · Fast switching speed
- High performance trench technology for extremely low R<sub>DS(ON)</sub>
- High power and current handling capability
- Qualified to AEC Q101





## Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage	-30	V
V <sub>GSS</sub>	Gate-Source Voltage	±25	V
I <sub>D</sub>	Continuous Drain Current @T <sub>C</sub> =25°C (Note 3)	<b>-40</b>	
	@T <sub>A</sub> =25°C (Note 1a)	-11	Α
	Pulsed, PW ≤ 100µs (Note 1b)	-100	_
P <sub>D</sub>	Power Dissipation for Single Operation (Note 1)	52	W
	(Note 1a)	3.8	
	(Note 1b)	1.6	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55 to +175	°C

## **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	2.9	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry.

For a copy of the requirements, see AEC Q101 at http://www.aecouncil.com/

Reliability data can be found at: http://www.fairchildsemi.com/products/discrete/reliability/index.html.

All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

Package Marking and Ordering Informatio
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Device Marking	Device	Reel Size	Tape Width	Quantity
FDD6685	FDD6685	13"	12mm	2500 units

Electric	al Characteristics	T <sub>A</sub> = 25°C unless otherwise noted				
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	urce Avalanche Ratings (Note	· 4)				
E <sub>AS</sub>	Single Pulse Drain-Source	I <sub>D</sub> = -11 A		42		mJ
I <sub>AS</sub>	Avalanche Energy  Maximum Drain-Source			-11	(	Α
IAS	Avalanche Current			-11		A
Off Chara	acteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-30			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu A$ , Referenced to 25°C		-24		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V},  V_{GS} = 0 \text{ V}$			-1	μΑ
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 25V$ , $V_{DS} = 0 V$			±100	nA
On Chara	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-1	-1.8	-3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu A$ , Referenced to 25°C		5		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = -10 \text{ V}, \qquad I_D = -11 \text{ A}$ $V_{GS} = -4.5 \text{ V}, \qquad I_D = -9 \text{ A}$ $V_{GS} = -10 \text{ V}, I_D = -11 \text{ A}, T_J = 125^{\circ}\text{C}$		14 21 20	20 30	mΩ
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = -10 \text{ V},  V_{DS} = -5 \text{ V}$	-20			А
<b>g</b> FS	Forward Transconductance	$V_{DS} = -5 \text{ V}, \qquad I_{D} = -11 \text{ A}$	7	26		S
Dynamic	Characteristics			•		
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -15 \text{ V},  V_{GS} = 0 \text{ V},$		1715		pF
Coss	Output Capacitance	f = 1.0 MHz		440		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			225		pF
R <sub>G</sub>	Gate Resistance	$V_{GS} = 15 \text{ mV},  f = 1.0 \text{ MHz}$		3.6		Ω
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = -15 \text{ V}, \qquad I_{D} = -1 \text{ A},$		17	31	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = -10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		11	21	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			43	68	ns
t <sub>f</sub>	Turn-Off Fall Time			21	34	ns
Qg	Total Gate Charge	$V_{DS} = -15V$ , $I_{D} = -11 A$ ,	R	17	24	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = -5 \text{ V}$	-	9		nC
Q <sub>gd</sub>	Gate-Drain Charge			4		nC
Drain-Sc	ource Diode Characteristics	and Maximum Ratings				
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = -3.2 \text{ A}  \text{(Note 2)}$		-0.8	-1.2	V
Trr	Diode Reverse Recovery Time	IF = −11 A,		26		ns
Qrr	Diode Reverse Recovery Charge	diF/dt = 100 A/μs		13		nC

## **Electrical Characteristics**

T<sub>A</sub> = 25°C unless otherwise noted

### Notes:

 R<sub>8JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>8JC</sub> is guaranteed by design while R<sub>8CA</sub> is determined by the user's board design.



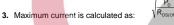
a)  $R_{\theta JA} = 40^{\circ} C/W$  when mounted on a  $1in^2$  pad of 2 oz copper



b)  $R_{\theta JA} = 96^{\circ}C/W$  when mounted on a minimum pad.

Scale 1:1 on letter size paper

**2.** Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%



where  $P_D$  is maximum power dissipation at  $T_C = 25^{\circ}C$  and  $R_{DS(on)}$  is at  $T_{J(max)}$  and  $V_{GS} = 10V$ .

**4.** Starting  $T_J = 25^{\circ}C$ , L = 0.69mH,  $I_{AS} = -11$ A



## **Typical Characteristics**

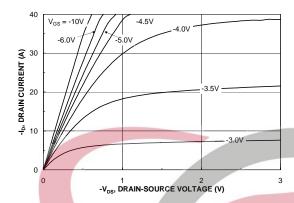


Figure 1. On-Region Characteristics.

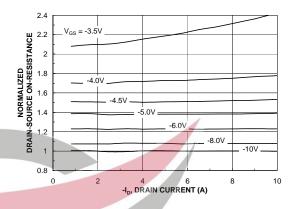


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

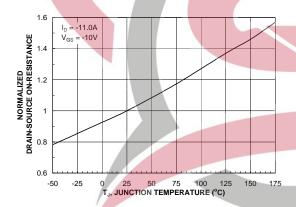


Figure 3. On-Resistance Variation with Temperature.

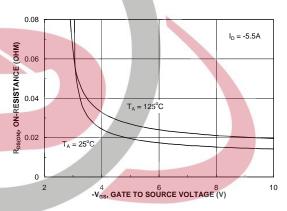


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

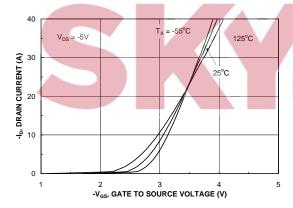


Figure 5. Transfer Characteristics.

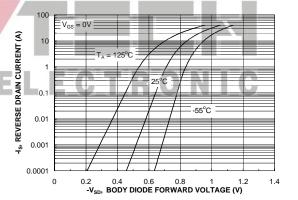
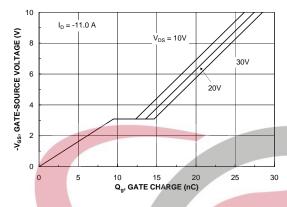


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

## **Typical Characteristics**



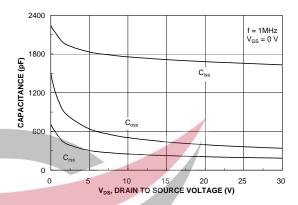
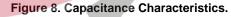
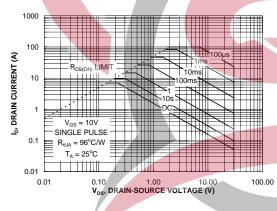


Figure 7. Gate Charge Characteristics.





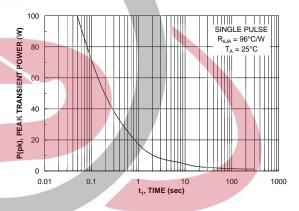


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

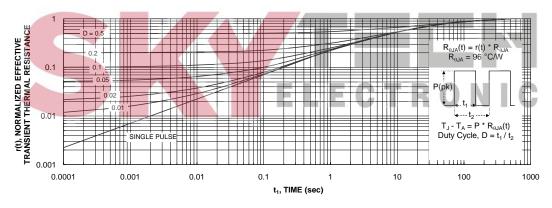


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.





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